Search Notes		

es	Application/Control No.	Applicant(s)/Patent under Reexamination	•
	10/673,963	SCHEIBLE ET AL.	
	Examiner	Art Unit	•
	Sunray Chang	2121	

	SEARCHED				
Class	Subclass	Date	Examiner		
700	20	3/25/2005	sc		
455	431	3/25/2005	sc		
180	65.3	3/25/2005	sc		
340	693.1	3/25/2005	sc		
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INTERFERENÇE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPAT, US_PGPUB, JPO, EPO, DERWENT, IBM_TDB)	3/25/2005	sc